

AMENDMENTS TO THE ABSTRACT

Please amend the Abstract of the Disclosure by replacing the Abstract of the Disclosure as originally filed with the amended Abstract of the Disclosure that is attached hereto.¹ as follows. The paragraph below is marked-up to show the changes made by this amendment:

A method for classifying defects of an object includes irradiating lights having different polarizations ~~wavelengths~~ onto the object to create an inspection spot on the object, collecting scattered lights generated by the irradiated lights scattering from the inspection spot, and classifying defects of the object by type of defect by analyzing the scattered lights. An apparatus for classifying defects of an object includes light creating means emitting lights having different polarizations ~~wavelengths~~ to create an inspection spot on the object, and a detecting member for collecting scattered lights that are created from the lights scattering from the inspection spot, wherein the scattered lights are analyzed and classified in accordance with defects positioned on the inspection spot of the object.

¹ MPEP § 608.01(b), examiner note no. 2.

ABSTRACT OF THE DISCLOSURE

A method for classifying defects of an object includes irradiating lights having different polarizations onto the object to create an inspection spot on the object, collecting scattered lights generated by the irradiated lights scattering from the inspection spot, and classifying defects of the object by type of defect by analyzing the scattered lights. An apparatus for classifying defects of an object includes light creating means emitting lights having different polarizations to create an inspection spot on the object, and a detecting member for collecting scattered lights that are created from the lights scattering from the inspection spot, wherein the scattered lights are analyzed and classified in accordance with defects positioned on the inspection spot of the object.